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Fault Detection and Diagnosis of Intelligent Mechatronic Systems

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Deadline for manuscript submissions:

closed (15 February 2020)

Message from the Guest Editors

Dear Colleagues,

Intelligent mechatronic systems (IMSs), such as intelligent vehicles, robots, airplanes, engines, and marine systems, have received considerable attention due to their practical applications in real lives. However, IMSs are generally complex due to the integrations of artificial intelligence and multidisciplinary features taken from mechanical engineering, computer engineering, electrical engineering, and control engineering. This integrated complexity leads to great challenges in system modeling and reliability testing due to different and complex failure modes. To achieve reliability requirements, fault detection and diagnosis are critical for the development of IMSs. With the network transmission, advances in sensing, information processing techniques, it is our opportunity to exploit them for the benefit of fault detection and diagnosis of IMSs.

Potential topics include but are not limited to:

- System modeling and analysis;
- Advanced sensing technologies for IMSs;
- Sensor fusion for IMSs;
- Fault detection of IMSs;
- Fault diagnosis of IMSs;
- Fault prediction of IMSs;
- Health monitoring of IMSs;

Guest Editors











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Message from the Editor-in-Chief

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